


Form PTO-1449 (REV. 8-83)		US Dept. of Commerce <b>PATENT &amp; TRADEMARK OFFICE</b>		ATTY DOCKET NO. 119243		APPLICATION NO. 10/808,523	
<div style="text-align: center;">  </div> <p style="text-align: center;">INFORMATION DISCLOSURE STATEMENT</p> <p style="text-align: center;">(Use several sheets if necessary)</p>				APPLICANT Hiroyuki HARA			
				FILING DATE March 25, 2004		GROUP 2858	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
	1	4,429,413	01/31/1984	David G. EDWARDS			
	2	6,049,620	04/11/2000	Alexander G. DICKINSON			
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
	3	EP 1 041 356 A1	10/04/2000	Europe			
	4	EP 0 969 477 A1	01/05/2000	Europe			
	5	JP A 58-27277 (w/Partial Eng. Trans. & Corresponding to U.S. 4,429,413)	02/17/1983	Japan			
	6	JP A 2000-028311 (w/Eng. Abstract and Translation)	01/28/2000	Japan			
	7	JP A 2002-340517 (w/Eng. Abstract and Translation)	11/27/2002	Japan			
	8	JP A 2003-090703 (w/Eng. Abstract and Translation)	03/28/2003	Japan			
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	9	Hiroyuki HARA et al., "Low Temperature Polycrystalline Silicon TFT Fingerprint Sensor with Integrated Comparator Circuit", IEEE, September 21-23, 2004, pages 403-406.					
	10	Ryuichi HASHIDO et al., "A Capacitive Fingerprint Sensor Chip Using Low-Temperature Poly-Si TFTs on a Glass Substrate and a Novel and Unique Sensing Method", IEEE JOURNAL OF SOLID-STATE CIRCUITS, February 2003,					
		vol. 38, no. 2, pages 274-280.					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: August 25, 2005